

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

 Print Format

 Your search matched **323** of **1038994** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

16 Emulation and enhancement of the Honeywell 2600 automatic test station
Wenzel, D.; Dichert, R.; Tse, M.;

AUTOTESTCON '99. IEEE Systems Readiness Technology Conference, 1999.

IEEE , 30 Aug.-2 Sept. 1999

Pages:439 - 450

[\[Abstract\]](#) [\[PDF Full-Text \(796 KB\)\]](#) IEEE CNF

17 An automatic two-area interconnected system load-frequency control design
Khatibi, M.H.; Mohammed, O.A.;

Southeastcon '94. 'Creative Technology Transfer - A Global Affair'. Proceedings of the 1994 IEEE , 10-13 April 1994

Pages:295 - 298

[\[Abstract\]](#) [\[PDF Full-Text \(248 KB\)\]](#) IEEE CNF

18 A framework for the development of object-oriented distributed systems
Bucci, G.; Mattolini, R.; Vicario, E.;

Autonomous Decentralized Systems, 1993. Proceedings. ISADS 93., International Symposium on , 30 March-1 April 1993

Pages:44 - 51

[\[Abstract\]](#) [\[PDF Full-Text \(544 KB\)\]](#) IEEE CNF

19 PROGEN: a program generator to generate conversion programs for test patterns
Schmitz, C.; Lackmann, R.; Rennett, T.;

Instrumentation and Measurement Technology Conference, 1992. IMTC '92., 9th IEEE , 12-14 May 1992

Pages:165 - 168

[\[Abstract\]](#) [\[PDF Full-Text \(232 KB\)\]](#) **IEEE CNF**

20 **IEEE standard for Digital Test Interchange Format (DTIF)**

IEEE Std 1445-1998 , 10 March 1999

[\[Abstract\]](#) [\[PDF Full-Text \(600 KB\)\]](#) **IEEE STD**

21 **Automatic synthesis of multi-tasking implementations from real-time object-oriented models**

Saksena, M.; Karvelas, P.; Wang, Y.;

Object-Oriented Real-Time Distributed Computing, 2000. (ISORC 2000)

Proceedings. Third IEEE International Symposium on , 15-17 March 2000

Pages:360 - 367

[\[Abstract\]](#) [\[PDF Full-Text \(92 KB\)\]](#) **IEEE CNF**

22 **Automatic generation and targeting of application specific operating systems and embedded systems software**

Gauthier, L.; Sungjoo Yoo; Jerraya, A.A.;

Design, Automation and Test in Europe, 2001. Conference and Exhibition 2001.

Proceedings , 13-16 March 2001

Pages:679 - 685

[\[Abstract\]](#) [\[PDF Full-Text \(516 KB\)\]](#) **IEEE CNF**

23 **Automatic full-custom design of high performance DSP chips**

Moscovitz, H.S.; Bullman, W.R.; Carelli, J.A.; Fadavi-Ardekani, J.; Mondal, K.; O'Donnell, G.D.;

Global Telecommunications Conference, 1988, and Exhibition. 'Communications for the Information Age.' Conference Record, GLOBECOM '88., IEEE , 28 Nov.-1 Dec. 1988

Pages:1400 - 1403 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(372 KB\)\]](#) **IEEE CNF**

24 **Automatic full-custom design of application specific DSP VLSI**

Moscovitz, H.S.; Bullman, W.R.; Carelli, J.A.; Davieau, L.A.; Fadavi-Ardekani, J.; Mondal, K.; O'Donnell, G.D.;

Circuits and Systems, 1988., IEEE International Symposium on , 7-9 June 1988

Pages:577 - 580 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(308 KB\)\]](#) **IEEE CNF**

25 **Providing Ada based test program and soft panel instrument controls**

Ziegler, J.; Grasso, J.M.; Burgermeister, L.G.; Mollod, L.D.;

AUTOTESTCON '89. IEEE Automatic Testing Conference. The Systems Readiness Technology Conference. Automatic Testing in the Next Decade and the 21st Century. Conference Record. , 25-28 Sept. 1989

Pages:187 - 194

[\[Abstract\]](#) [\[PDF Full-Text \(680 KB\)\]](#) **IEEE CNF**

26 **On the implementation of an analog ATPG: the nonlinear case**

Wey, C.-L.; Saeks, R.;

Instrumentation and Measurement, IEEE Transactions on , Volume: 37 , Issue:

2 , June 1988
Pages:252 - 258

[\[Abstract\]](#) [\[PDF Full-Text \(460 KB\)\]](#) IEEE JNL

27 Linking an automatic noise power measuring system to primary noise standards facilities: comparison of noise power measurements between PTB (Germany) and CMS (Taiwan, R.O.C.) in the radio frequency range between 2.0 GHz and 18.0 GHz

Buchholz, F.-I.; Schubert, D.; Kessel, W.; Chi, C.-M.; Yao, A.; Sun, W.W.;

Precision Electromagnetic Measurements, 1994. Digest., 1994 Conference on , 27 June-1 July 1994

Pages:260 - 261

[\[Abstract\]](#) [\[PDF Full-Text \(136 KB\)\]](#) IEEE CNF

28 A generic kinematics software package

Ramadorai, A.K.; Ganapathy, U.; Guida, F.;

Robotics and Automation, 1994. Proceedings., 1994 IEEE International Conference on , 8-13 May 1994

Pages:3331 - 3336 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(448 KB\)\]](#) IEEE CNF

29 Use of an automatic program generator for the study of IM control strategies

Glaos, S.; Yao, P.; Manesse, G.;

Computers in Power Electronics, 1994., IEEE 4th Workshop on , 7-10 Aug. 1994

Pages:266 - 271

[\[Abstract\]](#) [\[PDF Full-Text \(368 KB\)\]](#) IEEE CNF

30 Knowledge requirements for the automatic generation of project management reports

Korelsky, T.; McCullough, D.; Rambow, O.;

Knowledge-Based Software Engineering Conference, 1993. Proceedings., Eighth , 20-23 Sept. 1993

Pages:2 - 9

[\[Abstract\]](#) [\[PDF Full-Text \(628 KB\)\]](#) IEEE CNF

[Prev](#) [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [11](#) [12](#) [13](#) [14](#) [15](#) [16](#) [17](#) [18](#) [19](#) [20](#) [21](#) [22](#) [Next](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

 Print Format

 Your search matched **323** of **1038994** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

31 A self-checking PLA automatic generator tool based on unordered codes encoding
Torki, K.; Nicolaidis, M.; Fernandes, A.O.;

Design Automation. EDAC. Proceedings of the European Conference on , 25-28 Feb. 1991

Pages:510 - 515

[\[Abstract\]](#) [\[PDF Full-Text \(576 KB\)\]](#) **IEE JNL**
32 On automatic testpoint insertion in sequential circuits
Gundlach, H.H.S.; Muller-Glaser, K.-D.;

Test Conference, 1990. Proceedings., International , 10-14 Sept. 1990

Pages:1072 - 1079

[\[Abstract\]](#) [\[PDF Full-Text \(520 KB\)\]](#) **IEE JNL**
33 An expert test program generation system for per-pin testers
Walter, A.; Kleinman, Y.; Edelshteyn, L.; Gartner, J.;

Test Conference, 1988. Proceedings. 'New Frontiers in Testing', International , 12-14 Sept. 1988

Pages:665 - 668

[\[Abstract\]](#) [\[PDF Full-Text \(252 KB\)\]](#) **IEE JNL**
34 Automatic generation of self-scheduling programs
Foster, I.;

Parallel and Distributed Systems, IEEE Transactions on , Volume: 2 , Issue: 1 , Jan. 1991

Pages:68 - 78

[\[Abstract\]](#) [\[PDF Full-Text \(976 KB\)\]](#) **IEEE JNL**
35 Automatic template generation for solving n^2 -problems on parallel

systems with arbitrary topology*Lippert, T.; Palazzari, P.; Schilling, K.;*

Software Engineering for Parallel and Distributed Systems, 1997. Proceedings., Second International Workshop on , 17-18 May 1997

Pages:130 - 138

[\[Abstract\]](#) [\[PDF Full-Text \(580 KB\)\]](#) [IEE JNL](#)**36 Automatic generation of bridging code for accessing C++ from Java***Schade, A.;*

Technology of Object-Oriented Languages and Systems, 1997. TOOLS 25, Proceedings , 24-28 Nov. 1997

Pages:165 - 180

[\[Abstract\]](#) [\[PDF Full-Text \(924 KB\)\]](#) [IEE JNL](#)**37 The Automatic Efficient Test Generator (AETG) system***Cohen, D.M.; Dalal, S.R.; Kajla, A.; Patton, G.C.;*

Software Reliability Engineering, 1994. Proceedings., 5th International Symposium on , 6-9 Nov. 1994

Pages:303 - 309

[\[Abstract\]](#) [\[PDF Full-Text \(468 KB\)\]](#) [IEE JNL](#)**38 Automatic test generation for functional verification of microprocessors***Miyake, J.; Brown, G.; Ueda, M.; Nishiyama, T.;*

Test Symposium, 1994., Proceedings of the Third Asian , 15-17 Nov. 1994

Pages:292 - 297

[\[Abstract\]](#) [\[PDF Full-Text \(340 KB\)\]](#) [IEE JNL](#)**39 Automatic program generator for simulation-based processor verification***Iwashita, H.; Kowatari, S.; Nakata, T.; Hirose, F.;*

Test Symposium, 1994., Proceedings of the Third Asian , 15-17 Nov. 1994

Pages:298 - 303

[\[Abstract\]](#) [\[PDF Full-Text \(428 KB\)\]](#) [IEE JNL](#)**40 Automatic generation of visualization code for the Connection Machine***Purtilo, J.M.; Revis, D.R.;*

Frontiers of Massively Parallel Computation, 1990. Proceedings., 3rd Symposium on the , 8-10 Oct. 1990

Pages:158 - 161

[\[Abstract\]](#) [\[PDF Full-Text \(368 KB\)\]](#) [IEE JNL](#)**41 Automatic generation of visual programming environments***Costagliola, G.; Tortora, G.; Orefice, S.; de Lucia, A.;*

Computer , Volume: 28 , Issue: 3 , March 1995

Pages:56 - 66

[\[Abstract\]](#) [\[PDF Full-Text \(1664 KB\)\]](#) [IEEE JNL](#)**42 Corporate information systems and information technologies***Mitsumori, S.;*

Systems, Man and Cybernetics, IEEE Transactions on , Volume: 22 , Issue:
6 , Nov.-Dec. 1992
Pages:1323 - 1330

[\[Abstract\]](#) [\[PDF Full-Text \(728 KB\)\]](#) [IEEE JNL](#)

43 Bridging the gap between embedded test and ATE

Bell, M.; Danialy, G.; Howells, M.; Pateras, S.;

Test Conference, 2000. Proceedings. International , 3-5 Oct. 2000

Pages:55 - 63

[\[Abstract\]](#) [\[PDF Full-Text \(592 KB\)\]](#) [IEE JNL](#)

44 An automatic test case generator derived from state-based testing

Bor-Yuan Tsai; Stobart, S.; Parrington, N.; Mitchell, I.;

Software Engineering Conference, 1998. Proceedings. 1998 Asia Pacific , 2-4 Dec. 1998

Pages:270 - 277

[\[Abstract\]](#) [\[PDF Full-Text \(104 KB\)\]](#) [IEE JNL](#)

45 Automated validation test generation

Weber, R.; Thelen, K.; Srivastava, A.; Krueger, J.;

Digital Avionics Systems Conference, 1994. 13th DASC., AIAA/IEEE , 30 Oct.-3 Nov. 1994

Pages:99 - 104

[\[Abstract\]](#) [\[PDF Full-Text \(456 KB\)\]](#) [IEE JNL](#)

[Prev](#) [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [11](#) [12](#) [13](#) [14](#) [15](#) [16](#) [17](#) [18](#) [19](#) [20](#) [21](#) [22](#) [Next](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC](#)
[Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

 Print Format

Your search matched **323** of **1038994** documents.
 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 ATE tools for electronic system test

Brown, N.; Garrett, C.; Lea, S.M.;

Advances in Systems Engineering Tools and their Environments, IEE Colloquium on , 17 May 1988

Pages:2/1 - 2/4

[\[Abstract\]](#) [\[PDF Full-Text \(224 KB\)\]](#) IEEE CNF

2 Automated application software generator

Meyer, B.A.;

AUTOTESTCON '89. IEEE Automatic Testing Conference. The Systems Readiness Technology Conference. Automatic Testing in the Next Decade and the 21st Century. Conference Record. , 25-28 Sept. 1989

Pages:175 - 180

[\[Abstract\]](#) [\[PDF Full-Text \(316 KB\)\]](#) IEEE CNF

3 The simulation automation system (SAS); concepts, implementation, and results

Sungho Kang; Szygenda, S.A.;

Very Large Scale Integration (VLSI) Systems, IEEE Transactions on , Volume: 2 , Issue: 1 , March 1994

Pages:89 - 99

[\[Abstract\]](#) [\[PDF Full-Text \(756 KB\)\]](#) IEEE JNL

4 Analog automatic test plan generator-Integrating with modular analog IC design environment

Naiknaware, R.;

Computer Design: VLSI in Computers and Processors, 1993. ICCD '93. Proceedings., 1993 IEEE International Conference on , 3-6 Oct. 1993

Pages:318 - 321

[\[Abstract\]](#) [\[PDF Full-Text \(536 KB\)\]](#) IEEE CNF

5 An automatic test program generator

Ogata, T.; Ono, T.; Watanabe, T.; Ito, K.;

Industrial Electronics, Control and Instrumentation, 1991. Proceedings. IECON '91., 1991 International Conference on , 28 Oct.-1 Nov. 1991

Pages:1372 - 1374 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(180 KB\)\]](#) IEEE CNF

6 Qualification of automatic code generation using formal techniques

Coombes, A.; Armstrong, J.;

Practical Application of Formal Methods, IEE Colloquium on , 19 May 1995

Pages:7/1 - 7/2

[\[Abstract\]](#) [\[PDF Full-Text \(144 KB\)\]](#) IEEE CNF

7 IFTE verify probe capability

Frank, W.B.; Miller, J.F.; Stromecky, P.;

AUTOTESTCON '95. 'Systems Readiness: Test Technology for the 21st Century'. Conference Record , 8-10 Aug. 1995

Pages:31 - 34

[\[Abstract\]](#) [\[PDF Full-Text \(376 KB\)\]](#) IEEE CNF

8 The Automatic Element Routine Generator: an automatic programming tool for functional simulator design

Chuang, C.-I.; Szygenda, S.A.; Baker, J.D.;

Simulation Symposium, 1992. Proceedings. 25th Annual , 6-9 April 1992

Pages:84 - 90

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) IEEE CNF

9 A modern approach to digital fault simulation

Erath, P.; Loretz, R.;

AUTOTESTCON '89. IEEE Automatic Testing Conference. The Systems Readiness Technology Conference. Automatic Testing in the Next Decade and the 21st Century. Conference Record. , 25-28 Sept. 1989

Pages:118 - 123

[\[Abstract\]](#) [\[PDF Full-Text \(484 KB\)\]](#) IEEE CNF

10 Automatic test program generation for a block oriented VLSI chip design

Hapke, F.;

European Test Conference, 1989., Proceedings of the 1st , 12-14 April 1989

Pages:71 - 76

[\[Abstract\]](#) [\[PDF Full-Text \(500 KB\)\]](#) IEEE CNF

11 Mixed mode automatic test pattern generation

Geada, J.M.C.; Russell, G.;

Design for Testability, IEE Colloquium on , 16 May 1991

Pages:1/1 - 1/4

[\[Abstract\]](#) [\[PDF Full-Text \(260 KB\)\]](#) IEEE CNF

12 Power transformer automatic testing equipment based on discrete sampling

Li, Y.D.; Huo, C.Y.;

Industrial Technology, 1994. Proceedings of the IEEE International Conference on , 5-9 Dec. 1994

Pages:406 - 409

[\[Abstract\]](#) [\[PDF Full-Text \(272 KB\)\]](#) IEEE CNF

13 PENTAG-a Petri net based automatic test pattern generator for sequential digital circuits

Witts, G.; Alshahib, I.;

Testing-the Gordian Knot of VLSI Design, IEE Colloquium on , 28 May 1993

Pages:10/1 - 10/5

[\[Abstract\]](#) [\[PDF Full-Text \(232 KB\)\]](#) IEE CNF

14 Next Generation Test Generator (NGTG) interface to Automatic Test Equipment (ATE) for digital circuits

West, C.M.;

AUTOTESTCON '97. 1997 IEEE Autotestcon Proceedings , 22-25 Sept. 1997 .

Pages:126 - 128

[\[Abstract\]](#) [\[PDF Full-Text \(224 KB\)\]](#) IEEE CNF

15 ATPRG: an automatic test program generator using HDL-A for fault diagnosis of analog/mixed-signal integrated circuits

Wei-Hsing Huang; Chin-Long Wey;

Instrumentation and Measurement, IEEE Transactions on , Volume: 47 , Issue: 2 , April 1998

Pages:426 - 431

[\[Abstract\]](#) [\[PDF Full-Text \(192 KB\)\]](#) IEEE JNL

[1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [11](#) [12](#) [13](#) [14](#) [15](#) [16](#) [17](#) [18](#) [19](#) [20](#) [21](#) [22](#) [Next](#)
